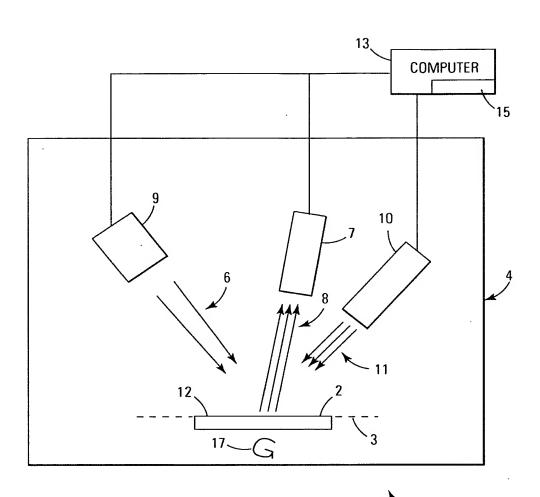
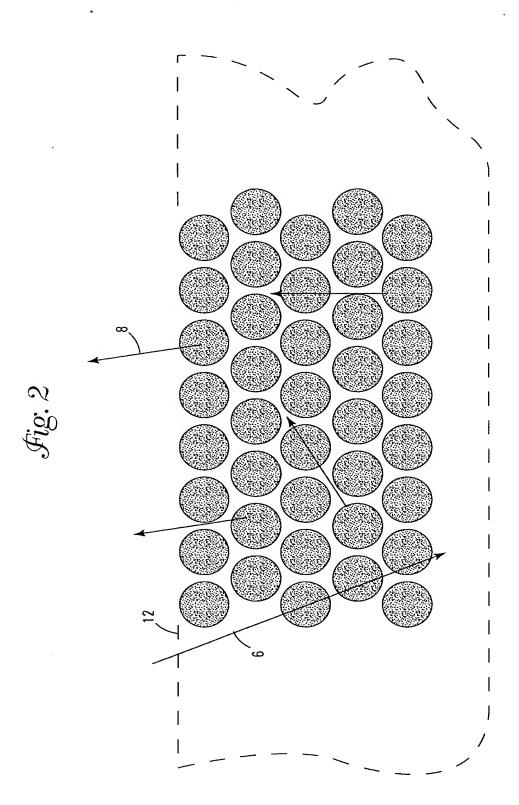
Title: SYSTEM AND METHOD FOR CHARACTERIZATION OF THIN FILMS Applicant(s): Larson et al., Serial No.: 10/003,224 Filed: October 26, 2001 Express Mail No.: EV 073731417 US Docket: 278.00060120

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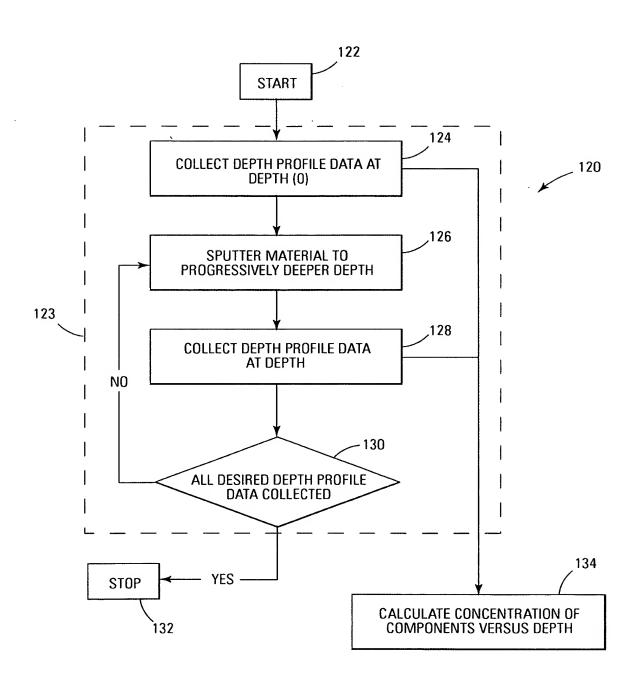


Fig. 3

Title: SYSTEM AND METHOD FOR CHARACTERIZATION OF THIN FILMS Applicant(s): Larson et al. Serial No.: 10/003,224 Filed: October 26, 2001

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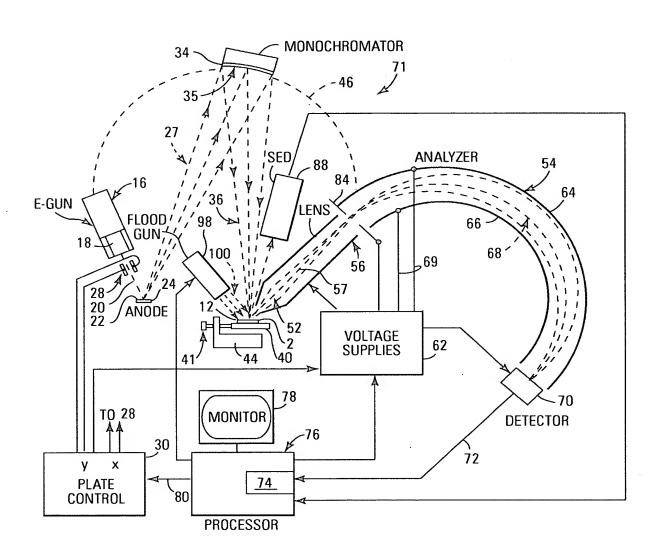


Fig. 4

Title: SYSTEM AND METHOD FOR CHARACTERIZATION OF THIN FILMS Applicant(s): Larson et al.

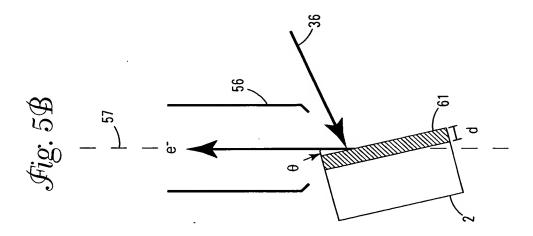
Serial No.: 10/003,224

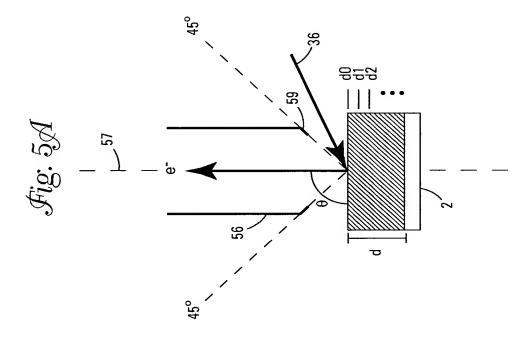
Express Mail No.: EV 073731417 US

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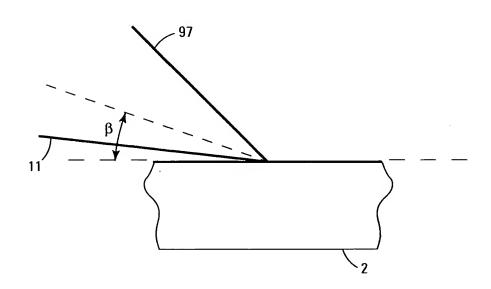


Fig. 6

Title: SYSTEM AND METHOD FOR CHARACTERIZATION OF THIN FILMS

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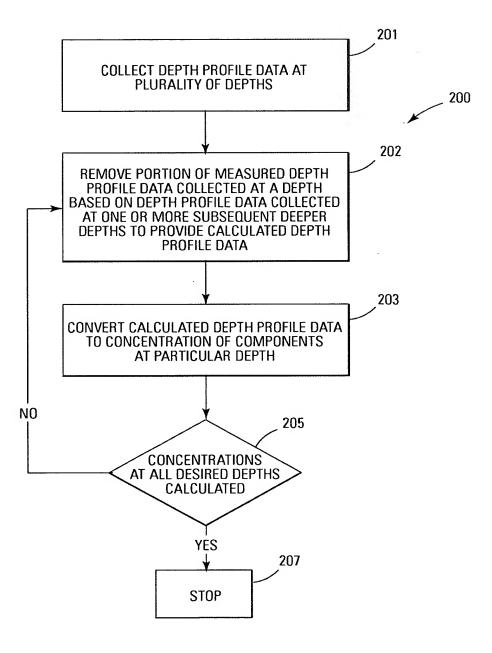


Fig. 7

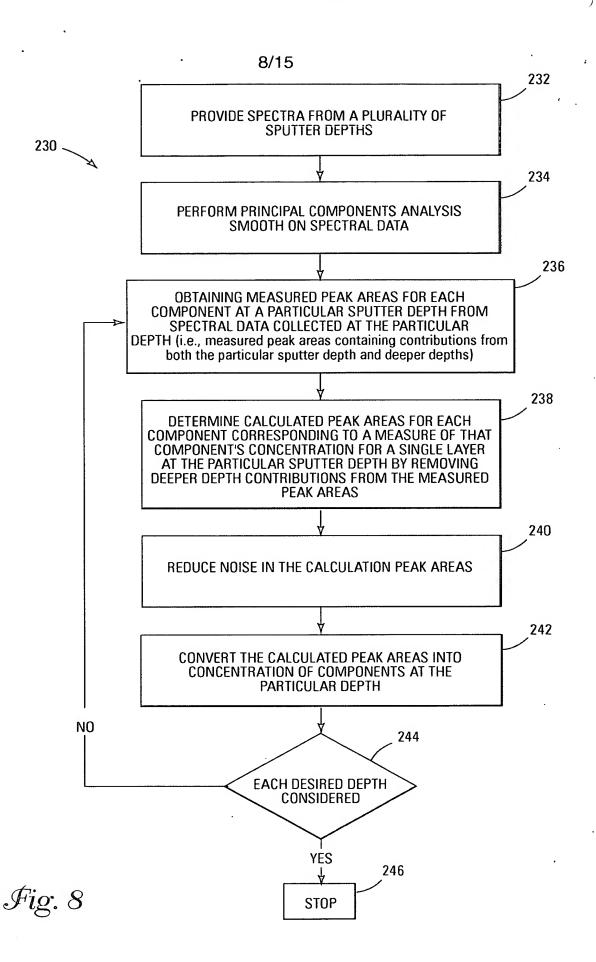
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Title: SYSTEM AND METHOD OR CHARACTERIZATION OF THIN FILMS

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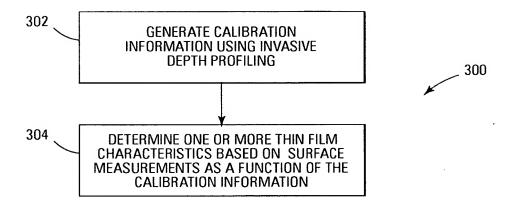


Fig. 9

Title: SYSTEM AND METHOD FOR CHARACTERIZATION OF THIN FILMS

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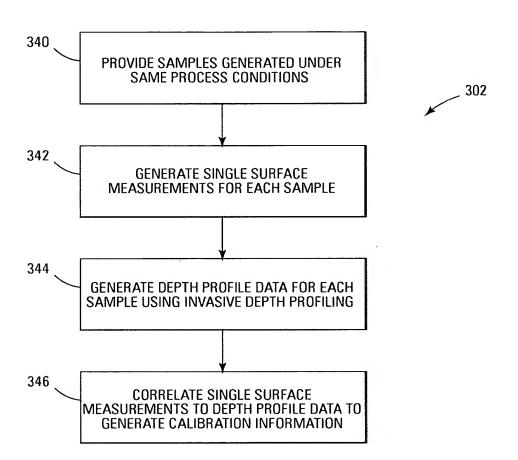


Fig. 10

Title: SYSTEM AND METHOS OR CHARACTERIZATION OF THIN FILMS

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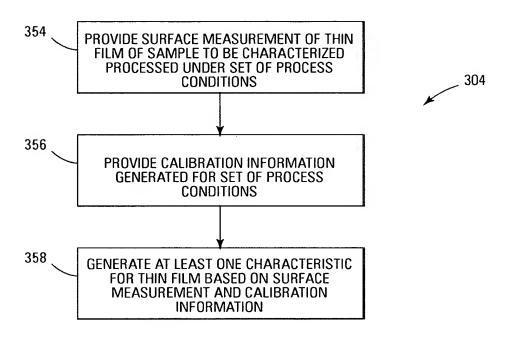


Fig. 11

Title: SYSTEM AND METHOD CHARACTERIZATION OF THIN FILMS Applicant(s): Larson et al.

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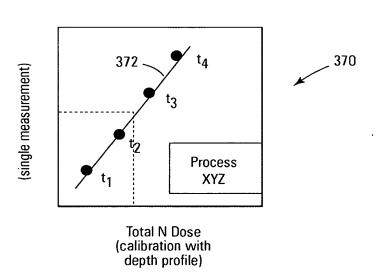


Fig. 12

Title: SYSTEM AND METHOD CHARACTERIZATION OF THIN FILMS

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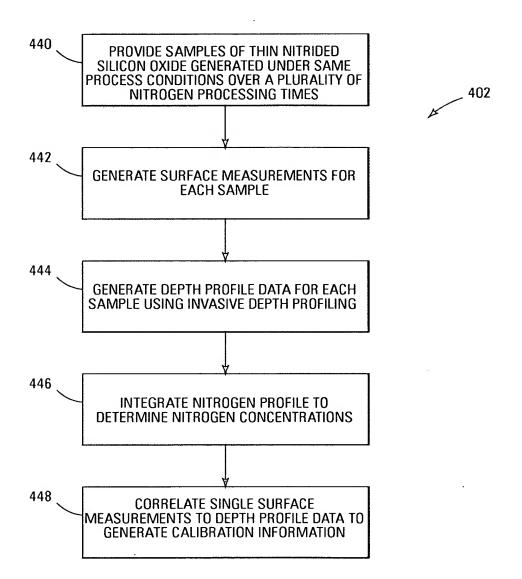


Fig. 13

Title: SYSTEM AND METHOD FO ARACTERIZATION OF THIN FILMS

Applicant(s): Larson et al.

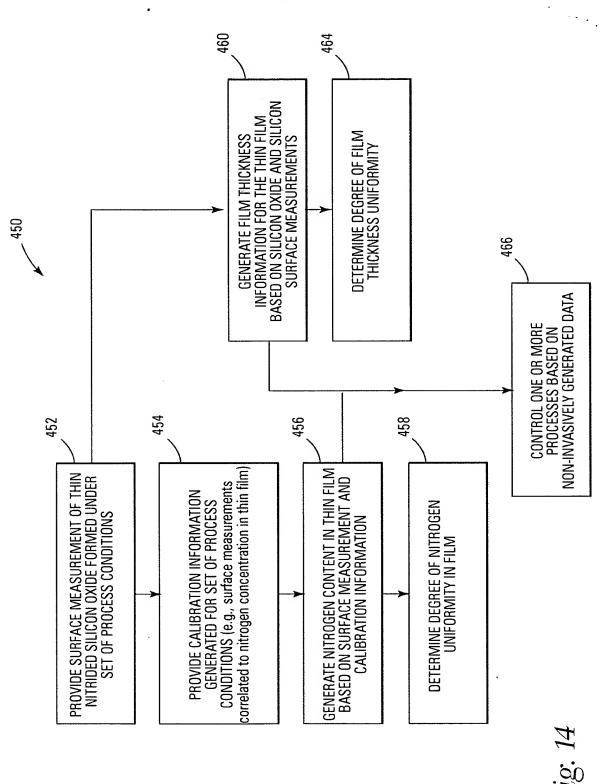
Serial No.: 10/003,224 Express Mail No.: EV 073731417 US

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